


<b>Issue Classification</b> 		Application/Control No.	Applicant(s)/Patent under Reexamination
		09667122	MOYER ET AL.
		Examiner	Art Unit
		Huisman, David J	2183

ORIGINAL		INTERNATIONAL CLASSIFICATION									
CLASS	SUBCLASS	CLAIMED			NON-CLAIMED						
712	205	G	0	6	F	9 / 00					
<b>CROSS REFERENCE(S)</b>											
						<b>CLASS</b>					
						<b>SUBCLASS (ONE SUBCLASS PER BLOCK)</b>					

<i>David J. Huisman</i> (Assistant Examiner)	6-14-06 (Date)	<b>EDDIE CHAN</b> <b>SUPERVISORY PATENT EXAMINER</b> <b>TECHNOLOGY CENTER 2100</b> (Primary Examiner)	6/16/06 (Date)	O.G. Print Claim(s) 1	O.G. Print Figure 2
<i>David J. Huisman</i> (Legal Instruments Examiner)	6-22-06 (Date)				
		<b>Total Claims Allowed:</b> 21			